OUTPUT Frequency

80 MHz Level +13 dBm ±2 dB into 50 ohms STABILITY

Aging

 1×10^{-6} first year after 30 days operating, typical 5×10^{-7} second year, typical 3×10^{-7} per year thereafter, typical

Phase Noise L(f), dBc/Hz

	(7)	Each Axis					
	Static	Dynamic, goal					
5 Hz	-80	-71					
10 Hz	-98	-65					
15 Hz	-103	-61					
16 Hz	-104	-64					
25 Hz	-108	-60					
26 Hz	-109	-66					
33 Hz	-115	-63					
100 Hz	-130						
1 kHz	-158						
10 kHz	-174						
100 kHz							
Temperature Stability							
±5 x 10 ⁻⁷ , -40° to +63°C (Ref +25°C)							
Harmonics, Sub-harmonics							
≤-30 dBc							
Non-Harmonic Spurious							
-80 dBc, max							
MECHANICAL	-						
Dimensions							
2.386 x 2 x	1.06"						
Connectors							
	d solder p	ins on one side					
Packaging							
Nickel-plate	ed machir	ned					
aluminum I	nousing						
Mounting							
		2-56, 4 places					
Threaded inserts on sides, 16 places							
(provisions for shock mounts)							

POWER REQUIREMENTS

Warm-Up Power

≤ 6 Watts for 5 minutes at +25°C **Total Power** ≤ 3.5 Watts at +25°C

Supply Voltage

+15 VDC ±5%

Mechanical Tuning $+4 \times 10^{-6}$ **Electrical Tuning** $\pm 2 \times 10^{-7}$ min. 0 to ± 10 VDC Negative slope CRYSTAL Type 80 MHz SC-cut (low-g) ENVIRONMENTAL Acceleration Sensitivity 5×10^{-10} /g per axis, typical Shock Designed to survive operational and nonoperational testing with degraded phase noise and spurious signal performance during shock. No performance data is provided. No testing is provided on production units. 30g, 11 ms, half sine, horizontally 12g, 11 ms, half sine, vertically 3 blows in each axis, both ways Vibration Designed to survive operational and nonoperational testing per MIL-STD-167-1A Type I, with degraded phase noise and spurious

signal performance during vibration. Tested at 5, 15, 16, 25, 26 and 33 Hz only. 5 Hz* to 15 Hz 0.030 ±0.006 inSA 16 Hz to 25 Hz 0.020 ±0.004 inSA 26 Hz to 33 Hz 0.010 ±0.002 inSA * Lowest offset available on in-house testing

capabilities Humidity

ADJUSTMENT

Designed to meet operational and nonoperational testing per MIL-STD-810, Method 507.4, but no testing is provided on production units. Vital components shall be conformal coated.

High Storage Temperature

Designed to survive non-operational testing per MIL-STD-810, Method 501.4, Procedure I. No testing is provided on production units.

High Operation Temperature

Designed to meet operational testing per MIL-STD-810, Method 501.4, Procedure II. No testing is provided on production units.

REV	DATE	REVISION RECORD	DWN	AUTH
-	03-03-11	Initial Release	PAC	
А	05-02-13	Updated Title	PAC	

Low Storage Temperature

Designed to survive non-operational testing per MIL-STD-810, Method 502.4, Procedure I. No testing is provided on production units.

Low Operation Temperature

Designed to meet operational testing per MIL-STD-810, Method 502.4, Procedure II. No testing is provided on production units.

OTHER

Special

The electrical design of this oscillator incorporates High Reliability & COTS components, for an extended life span.

Design

PCBs secured for operation in a dynamic environment

Test Data – Production Units

Output Level

Phase Noise – Static and Dynamic

Temperature Stability

Harmonics, Subs, Spurious

Current Draw - Warm-up and Total

Tuning – ET and MT

Acceleration Sensitivity

Environmental Qualification Testing

(On one (1) randomly selected production unit only – Qual testing is listed as a separate line item on the quote)

- Pre-Environmental Electrical Tests
- High Storage Temperature
- High Operating Temperature
- Low Storage Temperature
- Low Operating Temperature
- Shock
- Vibration
- Humidity
- Post-Environmental Electrical Tests

Wenzel Associates, Inc.										
80 MHz ULN II Crystal Oscillator										
^{P/N:} 501-23707	Rev:	Date 0	5-02-13	Drawn:		Ref: 19435a				
Tolerances: (except as noted) Dimensions are in inches	0.XX Dec: ±0.03				Page 1 of 2					

507.

